

Search Notes

Application/Control No.

10/822,444

Examiner

Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

BERAN ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
715	735,734, 736,744, 746,747, 717	6/23/2007	LEE
11	853,854	11	1/

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
715	as above	6/23/2007	LEE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR